

<b>Notice of References Cited</b>	Application/Control No. 10/766,937	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Quang T Van	Art Unit 3742	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,270,510	12-1993	Aoki et al.	219/706
	B	US-4,518,839	05-1985	Taguchi et al.	219/713
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 08171987 A	07-1996	Japan	SHIRAKAWA, HISATO	H05B 06/78
	O	JP 09050884 A	02-1997	Japan	MAKITA, MINORU	H05B 06/64
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.